

<b>Notice of References Cited</b>	Application/Control No. 10/693,736	Applicant(s)/Patent Under Reexamination YUAN ET AL.	
	Examiner Chau Nguyen	Art Unit 2176	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0161796	10-2002	Sylthe, Olav A.	707/500
*	B	US-2004/0073872	04-2004	Yalovsky et al.	715/517
*	C	US-2003/0145279	07-2003	Bourbakis et al.	715/511
*	D	US-2003/0167448	09-2003	Williamson et al.	715/517
*	E	US-2003/0130837	07-2003	Batchilo et al.	704/9
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.